

***Continued Examination Under 37 CFR 1.114***

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 9/19/11 has been entered.

***Allowable Subject Matter***

2. Claims 74-77, 81-86, 88, 90-92, 94, 96, 98, 100-101 and 104-106, (renumber 1-22) are allowed.
3. The following is an examiner's statement of reasons for allowance: The present invention is directed to an RFID tag with tamper detection. Each independent claim identifies the uniquely distinct features "an RFID integrated circuit module an RFID antenna disposed on the first surface of the second substrate and electrically coupled to the RFID integrated circuit via a non-contact coupling; an electrically conductive region disposed on the second surface of the second substrate and electrically coupled to the RFID integrated circuit via a non-contact coupling; and a first adhesive layer between a surface of the RFID integrated circuit facing the second substrate and the first surface of the second substrate, the first adhesive layer attaching the RFID integrated circuit module to the second substrate; the RFID integrated circuit being fixed to the second surface of the first substrate by a second adhesive layer; at least one electrical coupling circuit on the second surface of the first substrate and connected to the RFID integrated circuit,

the at least one electrical coupling circuit electrically coupling the RFID integrated circuit to the electrically conductive region via a non-contact coupling, and the at least one electrical coupling circuit electrically coupling the RFID integrated circuit to the RFID antenna via a non-contact coupling; an adhesion modifying layer associated with the first and/or second adhesive layer, the adhesion modifying layer modifying adhesion of the RFID integrated circuit or the at least one electrical coupling circuit so that the RFID integrated circuit and/or the at least one electrical coupling circuit is modified if the RFID integrated circuit module is removed from the second substrate to indicate tampering of the RFID tag" in combination with the manner claimed.

The closest prior arts **Atherton** [US 6,888,509] and **Beigel** [US 6,181,287] disclose similarly inventions; accept for the distinction features above. Therefore, either singularly or in combination, fail to anticipate or render the above underlined limitations obvious.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to SON M. TANG whose telephone number is (571)272-2962. The examiner can normally be reached on 5/8.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Daniel Wu can be reached on (571)272-2964. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/S. M. T./  
Examiner, Art Unit 2612

/DANIEL WU/  
Supervisory Patent Examiner, Art Unit 2612